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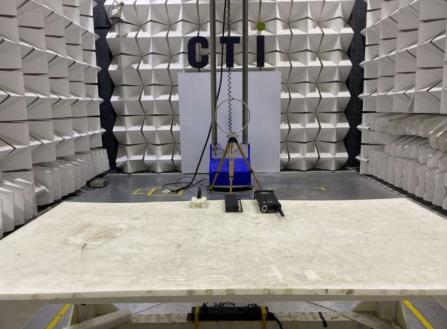
PHOTOGRAPHS OF TEST SETUP

Test model No.:VL150









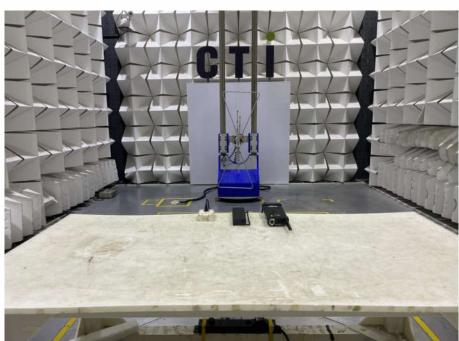


Radiated spurious emission Test Setup-1(Below 30MHz)









Radiated spurious emission Test Setup-2(Below 1GHz)











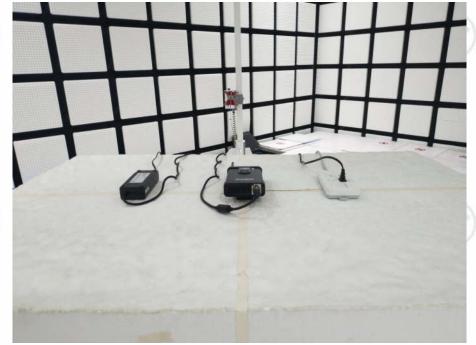








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Radiated spurious emission Test Setup-3(Above 1GHz)



Radiated spurious emission Test Setup-4(Above 1GHz)
There are absorbing materials under the ground.



















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